10/584668

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Gerhard Fritz, et al.

Art Unit : Unknown

Serial No.: N/A

Examiner: Unknown

Filed

: Herewith

Title

: ENERGY METERING SYSTEM

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

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Substitute Form PTO-1449 U.S. Department of Commerce (Modified) Patent and Trademark Office				
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Gerhard Fritz, et al.		
		Filing Date	Group Art Unit	

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publicatio n Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,417,792	07/09/2002	Eric King et al			
	AB	6,377,037	04/23/2002	Gordon Burns et al			
	AC	6,239,589	05/29/2001	Klaus Windsheimer			
	AD	6,373,415	04/16/2002	Eric King et al			
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	AI	5,545,981	08/13/1996	Dubin et al			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translat	ion
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AJ	2 319 345	05/20/1998	GB				
	AK	0 634 662	01/18/1995	ЕРО				
	AL	695 21 939	04/04/2002	Germany			Abstract	
	AM	689 20 984	07/06/1995	Germany			Abstract	
	AN	198 42 241	04/06/2000	Germany			Abstract	
	AO	101 62 259	07/17/2003	Germany			Abstract	
	AP							

	Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner	Desig.				
Initial	ID	Document			
	AQ	Nagura, H. et al "Correction Method for a Single Chip Power Meter"; IMTC 1994, pp 1313-1316 ISBN 0-7803-1880-3			
	AR				
-	AS				
	AT				

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if no	I of in conformance and not considered. Include copy of this form with
next communication to applicant.	